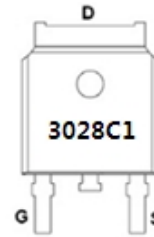
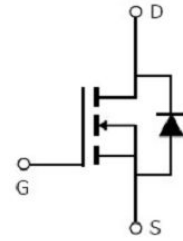


**Main Product Characteristics:**

$V_{DSS}$	30V
$R_{DS(on)}$	28mohm(typ.)
$I_D$	21A


**TO-252**

**Marking and pin Assignment**

**Schematic diagram**
**Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 175°C operating temperature


**Description:**

It utilizes the latest trench processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications

**Absolute max Rating:**

Symbol	Parameter	Max.	Units
$I_D @ TC = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	21①	A
$I_D @ TC = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	15①	
$I_{DM}$	Pulsed Drain Current ②	84	
$P_D @ TC = 25^\circ C$	Power Dissipation ③	28	W
	Linear Derating Factor	1.2	W/°C
$V_{DS}$	Drain-Source Voltage	30	V
$V_{GS}$	Gate-to-Source Voltage	± 20	V
$E_{AS}$	Single Pulse Avalanche Energy @ L=0.3mH	30	mJ
$I_{AS}$	Avalanche Current @ L=0.3mH	14	A
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to + 150	°C

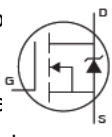
## Thermal Resistance

Symbol	Characterizes	Typ.	Max.	Units
R <sub>θJC</sub>	Junction-to-case ③	—	4.5	°C/W
R <sub>θJA</sub>	Junction-to-ambient (t ≤ 10s) ④	—	60	°C/W

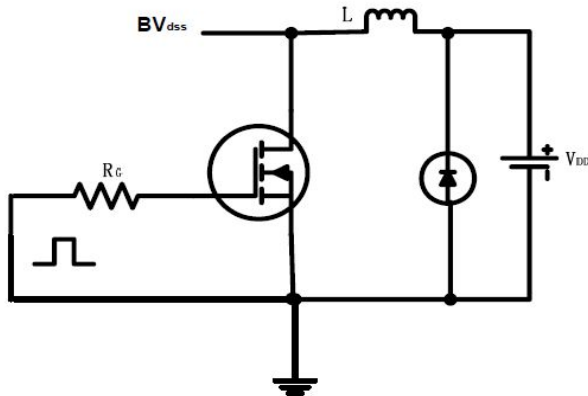
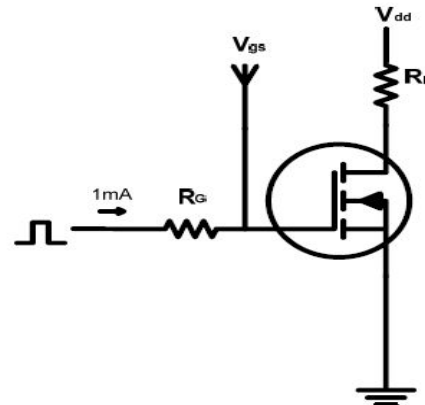
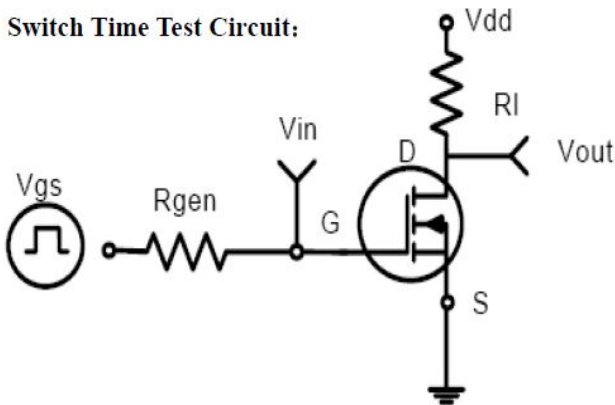
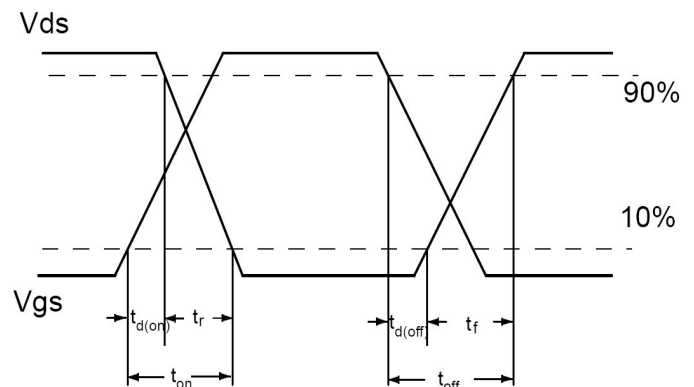
## Electrical Characterizes @T<sub>A</sub>=25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	30	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
R <sub>DS(on)</sub>	Static Drain-to-Source on-resistance	—	28	35	mΩ	V <sub>GS</sub> =10V, I <sub>D</sub> = 7A
R <sub>DS(on)</sub>	Static Drain-to-Source on-resistance	—	40	50	mΩ	V <sub>GS</sub> =4.5V, I <sub>D</sub> = 5A
V <sub>GS(th)</sub>	Gate threshold voltage	1	—	3	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA T <sub>J</sub> = 125°C
		—	1.11	—		
I <sub>DSS</sub>	Drain-to-Source leakage current	—	—	1	μA	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V T <sub>J</sub> = 125°C
		—	—	50		
I <sub>GSS</sub>	Gate-to-Source forward leakage	—	—	100	nA	V <sub>GS</sub> = 20V
		—	—	-100		V <sub>GS</sub> = -20V
Q <sub>g</sub>	Total gate charge	—	5.2	—	nC	I <sub>D</sub> = 7.5A, V <sub>DS</sub> =15V, V <sub>GS</sub> = 4.5V
Q <sub>gs</sub>	Gate-to-Source charge	—	2.1	—		
Q <sub>gd</sub>	Gate-to-Drain("Miller") charge	—	1.2	—		
t <sub>d(on)</sub>	Turn-on delay time	—	5	—	nS	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, R <sub>L</sub> =15Ω, R <sub>GEN</sub> =6Ω I <sub>D</sub> =1A
t <sub>r</sub>	Rise time	—	8	—		
t <sub>d(off)</sub>	Turn-Off delay time	—	17	—		
t <sub>f</sub>	Fall time	—	13	—		
C <sub>iss</sub>	Input capacitance	—	450	—	pF	V <sub>GS</sub> = 0V V <sub>DS</sub> = 15V f =1MHz
C <sub>oss</sub>	Output capacitance	—	110	—		
C <sub>rss</sub>	Reverse transfer capacitance	—	35	—		

## Source-Drain Ratings and Characteristics

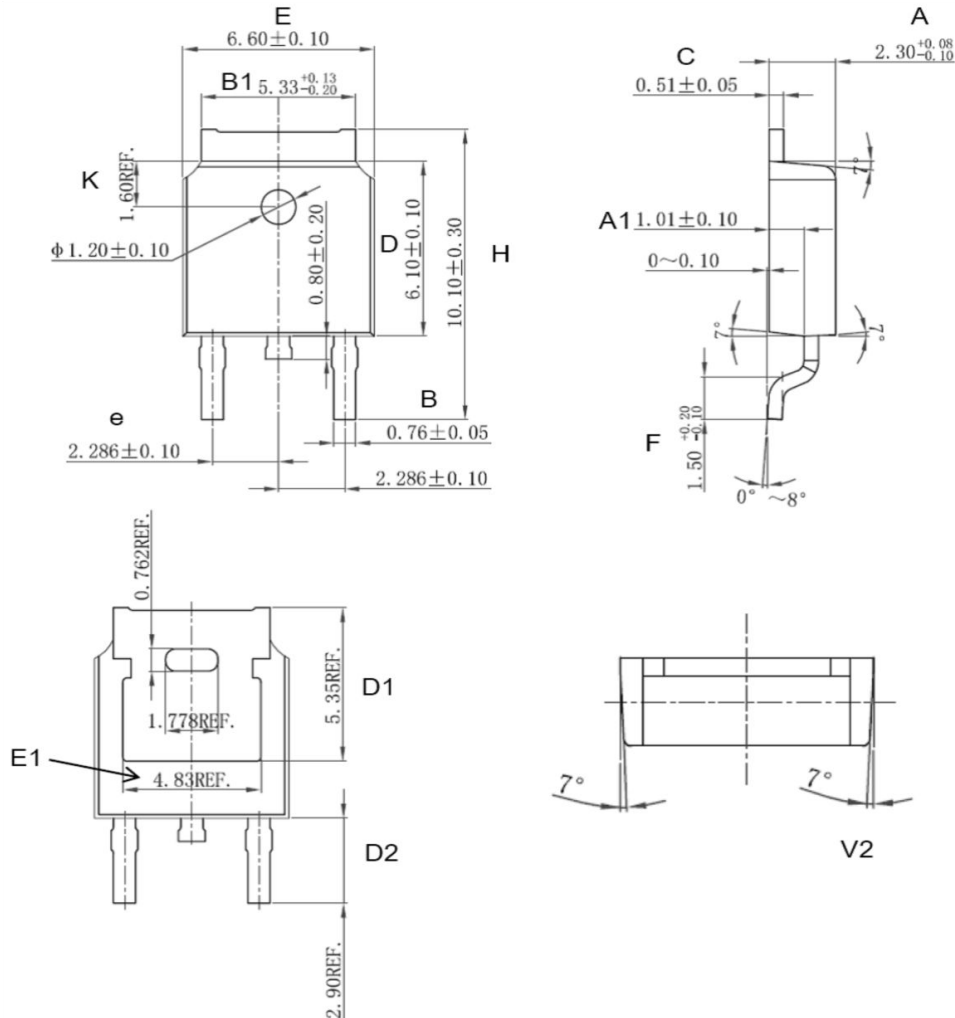
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	21①	A	MOSFET symb showing the integral reverse p-n junction diode. 
I <sub>SM</sub>	Pulsed Source Current (Body Diode)	—	—	84	A	
V <sub>SD</sub>	Diode Forward Voltage	—	0.72	1.2	V	I <sub>S</sub> =2.1A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	—	21	—	nS	T <sub>J</sub> = 25°C, I <sub>F</sub> =21A, di/dt = 100A/μs
Q <sub>rr</sub>	Reverse Recovery Charge	—	25.2	—	nC	

## Test circuits and Waveforms

**EAS test circuits:**

**Gate charge test circuit:**

**Switch Time Test Circuit:**

**Switch Waveforms:**


### Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ .
- ⑤ These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(MAX)} = 175^\circ\text{C}$ .

**Mechanical Data:**
**DPAK PACKAGE OUTLINE DIMENSION**


Symbol	Dimension In Millimeters			Dimension In Inches		
	Min	Nom	Max	Min	Nom	Max
A	2.200	2.300	2.380	0.087	0.091	0.094
A1	0.910	1.010	1.110	0.036	0.040	0.044
B	0.710	0.760	0.810	0.028	0.030	0.032
B1	5.130	5.330	5.460	0.202	0.210	0.215
C	0.460	0.510	0.560	0.018	0.020	0.022
D	6.000	6.100	6.200	0.236	0.240	0.244
D1	5.350 (REF)			0.211 (REF)		
D2	2.900 (REF)			0.114 (REF)		
E	6.500	6.600	6.700	0.256	0.260	0.264
E1	4.83 (REF)			0.190 (REF)		
e	2.186	2.286	2.386	0.086	0.090	0.094
H	9.800	10.100	10.400	0.386	0.398	0.409
F	1.400	1.500	1.700	0.055	0.059	0.067
K	1.600 (REF)			0.063 (REF)		
V2	8° (REF)			8° (REF)		

**Ordering and Marking Information**
**Device Marking: 3028C1**

**Package (Available)**  
**DPAK (TO-252)**  
**Operating Temperature Range**  
**C : -55 to 150 °C**

**Devices per Unit**
**Option1:**

Package Type	Units/Tape	Tapes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
TO-252	2500	2	5000	7	35000

**Option2:**

Package Type	Units/Tape	Tapes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
TO-252	2500	1	2500	10	25000

**Reliability Test Program**

Test Item	Conditions	Duration	Sample Size
High Temperature Reverse Bias(HTRB)	$T_j=150^{\circ}\text{C}$ @ 80% of Max $V_{DSS}/V_{CES}/V_R$	168 hours 500 hours 1000 hours	3 lots x 77 devices
High Temperature Gate Bias(HTGB)	$T_j=150^{\circ}\text{C}$ @ 100% of Max $V_{GSS}$	168 hours 500 hours 1000 hours	3 lots x 77 devices

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